

May 2000

FQPF5P20

200V P-Channel MOSFET

General Description

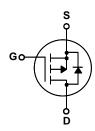
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters.

Features

- -3.4A, -200V, $R_{DS(on)}$ = 1.4 Ω @V_{GS} = -10 V Low gate charge (typical 10 nC)
- Low Crss (typical 12 pF)
- Fast switching
- 100% avalanche tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQPF5P20	Units	
V _{DSS}	Drain-Source Voltage		-200	V	
I _D	Drain Current - Continuous (T _C = 25°C)		-3.4	А	
	- Continuous (T _C = 100°C)		-2.15	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	-13.6	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	330	mJ	
I _{AR}	Avalanche Current	(Note 1)	-3.4	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	3.8	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-5.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		38	W	
	- Derate above 25°C		0.3	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

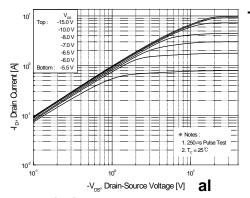
Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.29	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-200			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-0.17		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -200 V, V _{GS} = 0 V			-1	μА
		V _{DS} = -160 V, T _C = 125°C			-10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.7 A		1.1	1.4	Ω
g _{FS}	Forward Transconductance	V _{DS} = -40 V, I _D = -1.7 A (Note 4)		2.15		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		330 75	430 98	pF pF
	' '					
C _{rss}	Reverse Transfer Capacitance			12	15	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -100 V, I _D = -4.8 A,		9	28	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		70	150	ns
t _{d(off)}	Turn-Off Delay Time			12	35	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		25	60	ns
Qg	Total Gate Charge	$V_{DS} = -160 \text{ V}, I_{D} = -4.8 \text{ A},$		10	13	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V		2.8		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		5.2		nC
	ource Diode Characteristics ar	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				-3.4	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F				-13.6	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_{S} = -3.4 \text{ A}$			-5.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = -4.8 \text{ A,}$		175		ns
Q_{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		1.07		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 42.8mH, I_{AS} = -3.4A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq -4.8A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2% 5. Essentially independent of operating temperature

· Improved dv/dt capability



Typic Ч_D, Drain Current [A] $-V_{GS}$, Gate-Source Voltage [V]

Characteristics
Figure 1. On-Region Characteristics

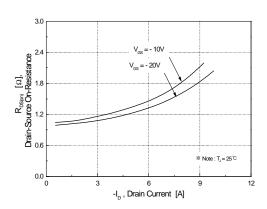


Figure 2. Transfer Characteristics

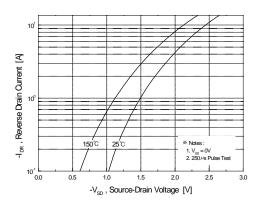


Figure 3. On-Resistance Variation vs. **Drain Current and Gate Voltage**

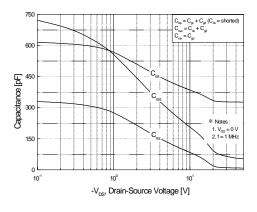


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

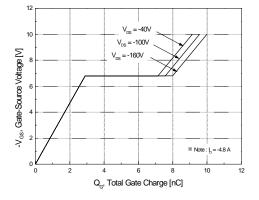
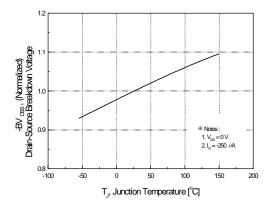


Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)



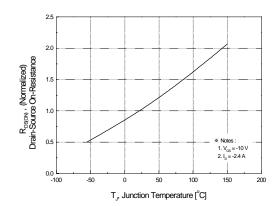
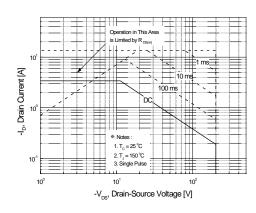


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



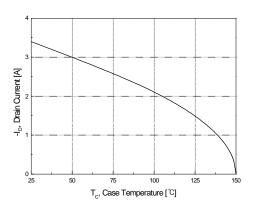


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

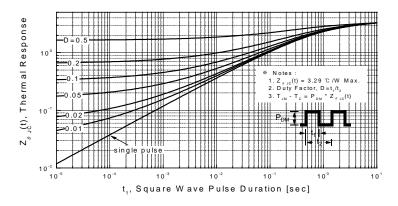
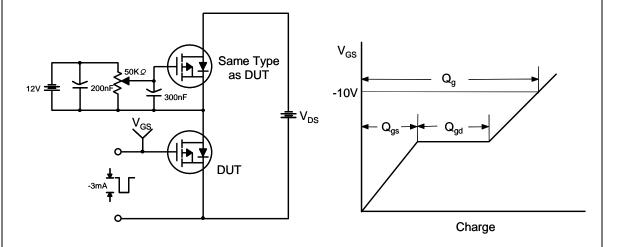


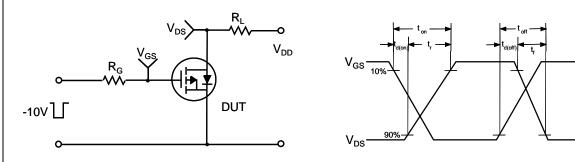
Figure 11. Transient Thermal Response Curve

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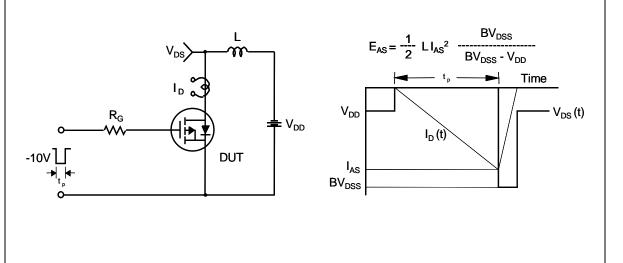
Gate Charge Test Circuit & Waveform



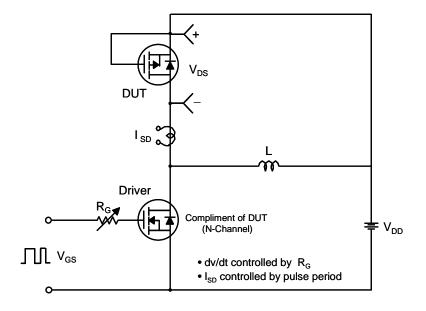
Resistive Switching Test Circuit & Waveforms

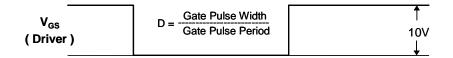


Unclamped Inductive Switching Test Circuit & Waveforms

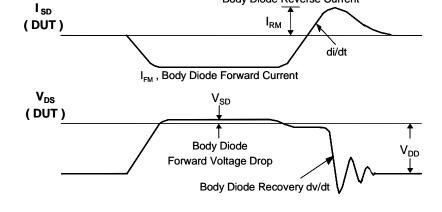


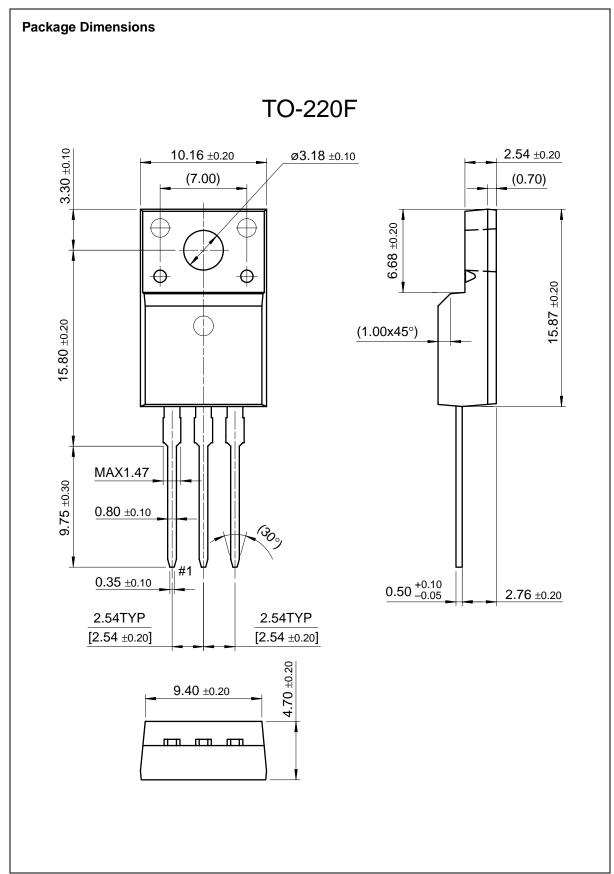
Peak Diode Recovery dv/dt Test Circuit & Waveforms





Body Diode Reverse Current





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